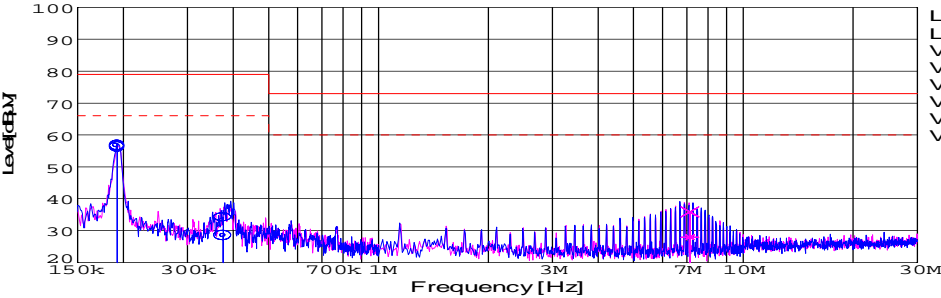
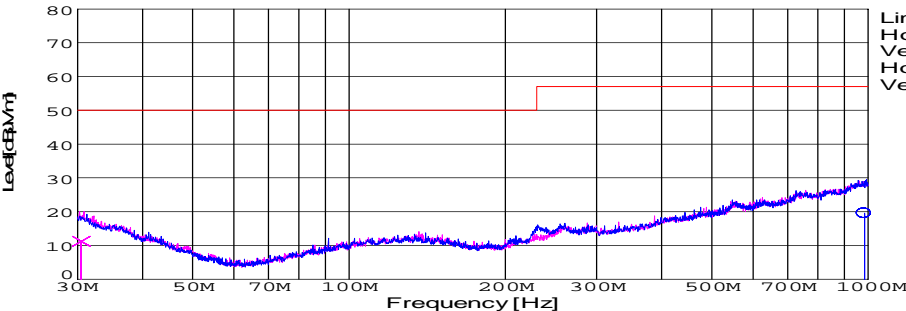


DATA SHEET							Date	06-Feb-09		
Model	SUTS32405						Temp.	25 degreeC		
Test	EMI Line conduction & Radiated emission						Humid.	45 %RH		
							Tested by	D.Joboji		
LINE CONDUCTION										
Model Name : SUTS32405			Temp. : 25							
Model No. :			Humi. : 45							
Serial No. :			Date : 2009/2/6 19:04							
Points : 3			Test Equip. : R3132,ESPC							
Detector : PEAK/QP/Ave.			Load Line : 10mm							
Line Mode : VA/VB			Comment :							
Power Supply : DC 24V										
Limit1: [EN 55022] Class A(QP)										
Limit2: [EN 55022] Class A(Ave.)										
							Limit1(QP) Limit2(Ave.) VA(PEAK) VB(PEAK) VA(QP) VA(Ave.) VB(QP) VB(Ave.)			
							DC 24V			
Frequency [MHz]	Meter Reading (Ave.)[dBuV]	Meter Reading (QP)[dBuV]	Factor [dB]	Level(Ave.) [dBuV]	Level(QP) [dBuV]	Line	Limit(Ave.) [dBuV]	Limit(QP) [dBuV]	Margin(Ave.) [dB]	Margin(QP) [dB]
0.1924	46.9	46.4	9.8	56.7	56.2	VA	66	79	9.3	22.8
0.3761	18.5	24.3	9.9	28.4	34.2	VA	66	79	37.6	44.8
7.1398	17.8	25.8	10.1	27.9	35.9	VB	60	73	32.1	37.1

RADIATED EMISSION										
Model Name : SUTS32405			Temp. : 25							
Model No. :			Humi. : 45							
Serial No. :			Date : 2009/2/6 19:33							
Points : 2			Test Equip. : R3132,ESPC							
Detector : PEAK/QP			Load Line : 10mm							
Polarization : Hori. & Vert.			Comment :							
Power Supply : DC 24V										
Limit: [EN 55022] Class A<3m>										
							Limit(QP) Horizontal(PEAK) Vertical(PEAK) Horizontal(QP) Vertical(QP)			
							DC 24V			
Frequency [MHz]	MeterReading (QP)[dBuV]	Ant. Type	Antenna Factor[dB/m]	Cable & Preamp[dB]	Level(QP) [dBuV/m]	Angle [°]	Height[cm]	Polar.	Limit [dBuV/m]	Margin [dB]
984.297	23.5	BL	25.3	-29.3	19.5	125	135	Hori.	57	37.5
30.498	25.5	BL	18	-32.3	11.2	190	132	Vert.	50	38.8

DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission





Conditions

Test : EMI
Model Name : SUTS/SUTW 324□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

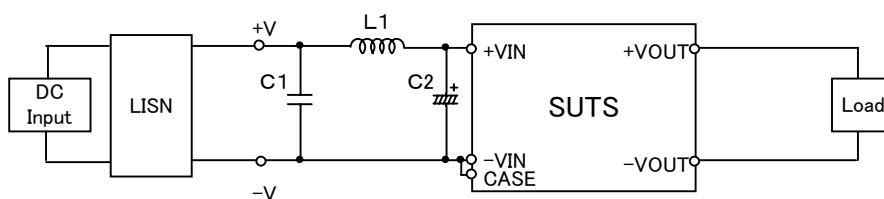


Fig.1 Testing circuitry 1

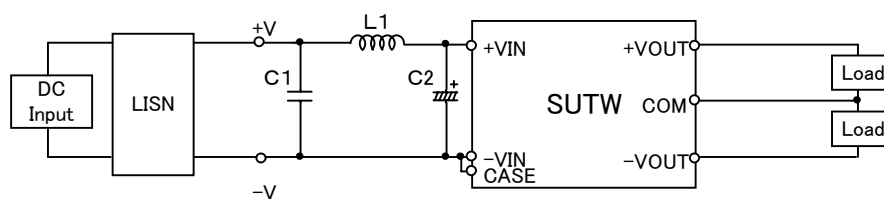


Fig.2 Testing circuitry 2

L1 :	10 μ H	CY3H-100	(KORIN ELECTRONICS)
C1 :	50V 0.47 μ F	C2012JB1H474K	(TDK)
C2 :	50V 47 μ F	UPW1H470M	(NICHICON)